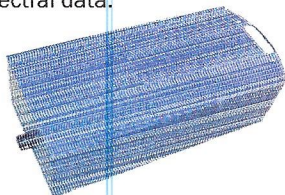


FEATURES

- Variable working width and spatial resolution.
- Variable working distance
- Integrated 12-bit data processing chain from object detection to direct control of the ejecting system
- Scan rate up to 1 kHz (with limited spectral range and/or local resolution)
- Possibility to teach up to 32 spectra
- Serial interface to the MMI - Computer (Gigabit Ethernet interface)
- Direct connection of up to 512 digital inputs and 512 digital outputs (interface to the EVK SIO System)
- Combined operation with EVK metal sensors possible

HELIOS COMPLETE NIR [in the NIR range up to 2.5 µm]

HELIOS COMPLETE is an integrated opto-electronic measuring and classification system, incorporating the complete hyperspectral processing chain that can sort different materials and products using parallel recorded NIR (up to 1.7µm) spectral data.



It consists of an optical assembly with lenses and spectro-scope for spatial and spectral resolution of the scanned line, a 2D-NIR sensor and a proprietary FPGA and DSP (FPGA - Field Programmable Gate Array; DSP

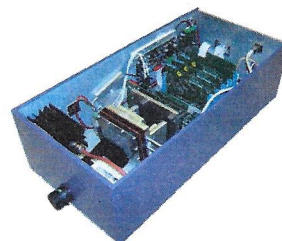
- Digital Signal Processors) based computing unit for fast processing and reduction of data and subsequent in-line classification of materials. The generated information can directly control pressurized air nozzle banks or can be handed over to a computer system.

"HELIOS Complete is designed for classifying and sorting bulk material.."

HELIOS COMPLETE is a stand-alone system that requires only a PC for teaching, parameterization and visualization of sorting statistics

Fields of Application

- Sorting of waste streams
- Food Processing
- Mining Industries
- Pharmaceutical Industries
- In-line quality control
- Diverse monitoring tasks



EXAMPLE OF SORTING RESOLUTION

1 HELIOS; 1m sorting width
2.5 m/s conveyor speed

HELIOS Complete; 120 Hz

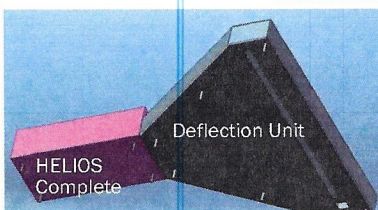
HELIOS Complete; 240 Hz

Classifications per second	Supported spectral points for classification	Size of the measuring grid based on 240 spatial pixels
31.000	316 (full spectrum)	4,2 x 20,8 mm
61.500	316 (full spectrum)	4,2 x 10,4 mm

Parallelising two or more Systems, spatial resolution orthogonal to the flow direction can be increased. Further spatial resolution in the flow direction can be increased by either decreasing conveyor speed or spectral range. Thus HELIOS Complete can flexibly fit demands for numerous applications.

EXAMPLE FOR THE WORKING DISTANCE (mm) BASED ON WORKING WIDTH AND FOCUS LENGTH

Working width (mm)	F=5mm	F=8mm	F=12mm	Spatial Resolution (mm)
500	350	530	790	2
1000	650	1050	1570	4
1500	980	1570	2350	6
2000	1300	2090	3130	8
2500	1630	2610	3910	10



Note: The distance between the conveyor belt and the HELIOS Complete can be reduced to adequate values by using a deflection unit with integrated mirror.

HELIOS COMPLETE NIR [Technical Data]



Hardware

Dimensions (without fore optic)
System of protection
Case material
Overall weight

Electronic Data

Voltage
Current consumption
Interfaces

System

Sensor
Cooling
Pixel rate (sensor)
Pixels (sensor)
Size of pixels
Data depth
Spectral range
Spectral resolution
Spectral sampling
Slit
Lens
Keystone
Smile
Spectral operations
Spatial operations
Intensity operations
Processing options
Working temperature
Storage temperature
Relative atmospheric humidity
Background detection
Parallel loaded reference spectra
Max. No. of classifiers
Classification configuration
Frame rate:
HELIOS Basic
HELIOS Standard
Clock rate of data processing
Sorting phases
Valves for each sorting phase

VIS/NIR (preliminary)	NIR	SWIR (preliminary)
590 x 260 x 155 mm	590 x 260 x 155 mm	595 x 300 x 155 mm
IP55	IP55	IP55
Aluminium		
Approx. 14.2 kg	Approx. 14.2 kg	Approx. 18.0 kg
+24V DC +/-15%; up to 3000V protection from fast transient / burst		
1.5 A	2.5 A	7 A
Gigabit Ethernet		
CMOS	InGaAs	HgCdTe
Peltier, natural convection		
40 MHz	40 MHz	20 MHz
320 (spectral) x 256(spatial)		
7x7 µm	30x30 µm	30 x 30 µm
10 bits	12 bits	12 bits
0.4 - 1.0 µm	1.1 - 1.7 µm 0.9 - 1.7 µm	1.5 - 2.5 µm 1.3 - 2.3 µm
9 nm (FWHM @ 30 µm slit)		
-	1.9 / 2.5 nm	3.2 nm
30, 50, 80, 100 µm		
F=5mm; F=8mm; F=12mm; Standard C-Mount, optional fiber optic mounting		
Corrected (less than 1 pixel)		
Corrected (less than 1 pixel)		
Onboard smile correction, spectral calibration, optional ROI setting and binning		
Onboard keystone correction, optional ROI setting and binning		
Non uniform intensity correction, bad-pixel correction		
Intensity; 1 st or 2 nd derivative; Fixed zero or floating zero (max/min) normalizing		
0 - 40 °C	0 - 40 °C	0 - 40 °C
-25 °C to +75 °C		
8 - 80 %		
Yes; undercut between background and taught spectra or rather not-taught spectra		
32 (can be associated to 8 spectra groups)		
8		
Selecting spectral details and weighting		
120 Hz full frame 240 Hz full frame		60 Hz full frame 120 Hz full frame
(By decreasing the spectral range and spatial resolution (overall ROI) the scan rate can be increased up to 1 kHz)		
Optionally 1ms / 2ms / 5ms		
2-way system or 3-way system		
8, 16, 32, 64, 128		
Independent light (if permitted light is possible)		